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In re Patent No. 6,782,344
Issue Date: August 24, 2004
Application No. 10/034,168
Filed: December 28, 2001
Attorney Docket No. 500014-93

**OFFICE OF PETITIONS
ON PETITION**

This is a decision on the petition under 37 CFR 3.81(b), filed May 11, 2005, to accept the addition of the second assignee on the front page of the above-identified patent.

The petition is **dismissed**.

Petitioner requests issuance of a certificate of correction to add the second assignee's name of "Nippon Gear Co., Ltd. Kanagawa-Ken (JP)." 37 CFR 3.81(a) permits the patent to issue to the assignee, provided that, at the time the issue fee is paid, the name of an assignee is provided. 37 CFR 3.81(b) permits the patent to issue in the name of an assignee if the assignment was submitted after payment of the issue fee but *prior to issuance of a patent*. The U.S. Patent and Trademark Office assignment records disclose that an assignment from inventors Haruo Ito, Susumu Watanabe, and Tomoaki Sumita to Nippon Gear Co., Ltd. was recorded on January 24, 2005, after the date of issuance of this patent. Accordingly, since the assignment was not submitted for recordation until after issuance of this patent, issuance of a certificate of correction would not be proper. Note also MPEP Section 307.

Further correspondence with respect to this matter should be addressed as follows:

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